PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/736,386)		
Filed:	December 15, 2003)	Conf. No.:	6227
		j		
Title:	METHOD FOR CALCULATING HIGH-RESOLUTION WAFER PARAMETER PROFILES	3))		
		j		
Inventors:	Bruce Whitefield et al.)		
Art Unit:	2128)		
Examiner:	Kimberly A. Thornwell)		
Atty. Ref:	03-1345)		

RESPONSE TO THE OFFICE ACTION MAILED JULY 7, 2008

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed July 7, 2008, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.